What is claimed is:

1	1.	A system for testing a DUT having a plurality of probe pads, comprising:
2		a. a forcing probe for contacting and applying a first electrical signal to a first
3		one of the plurality of probe pads;
4		b. a sensing probe for contacting said first one of the plurality of probe pads and
5		sensing a second electrical signal at said first one of said plurality of probe
6		pads; and
7		c. a variable power supply in electrical communication with said forcing probe
8		and said sensing probe, said variable power supply capable of adjusting said
9		first electrical signal based upon said second electrical signal.
1	2.	A system according to claim 1, further comprising a plurality of forcing probes and
2		a plurality of variable power supplies, each of said forcing probes being in electrical
3		communication with a corresponding one of said plurality of power supplies.
1	3.	A system according to claim 1, a voltmeter electrically connected between said
2		sensing probe and said variable power supply, said voltmeter for measuring said
3		second electrical signal.
1	4.	A system according to claim 1, further comprising a probe card, said probe card
2		supporting said forcing probe and said sensing probe.
1	5.	A system according to claim 1, further comprising first and second sensing electrodes
2		and a sensing instrument, said first sensing electrode in electrical communication
3		with said variable power supply, said second sensing electrode in electrical
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- 1 6. A system according to claim 5, wherein said sensing instrument is a current meter.
- 7. A system according to claim 1, further comprising a plurality of forcing probes, a plurality of variable power supplies and a switching matrix, said plurality of forcing probes being selectively connectable to said plurality of variable power supplies via said switching matrix.
- 1 8. A system according to claim 1, further comprising a feedback controller electrically connected between said sensing probe and said variable power supply.
 - 9. A method of testing a DUT having a plurality of probe pads, comprising the steps of:
 - a. providing a first electrical signal to one of the plurality of probe pads;
 - b. sensing a second electrical signal at said one of the plurality of probe pads; and
 - c. adjusting said first electrical signal based upon said second electrical signal.
 - 10. A method according to claim 9, further comprising the step of measuring a third electrical signal at a second one of the plurality of probe pads.
- 1 11. A method according to claim 9, wherein
- a. a plurality of first electrical signals are provided to a number of the plurality
 of probe pads;
- b. a plurality of second electrical signals are sensed at said number of the plurality of the probe pads; and
- 6 c. each of the first electrical signals is adjusted based upon said plurality of second electrical signals.

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- 12. A method according to claim 11, wherein said plurality of first electrical signals is provided via a plurality of forcing probes and a plurality of power supplies each in electrical communication with a corresponding one of said plurality of forcing probes.
- 1 13. A method according to claim 12, further comprising the step of selectively coupling said forcing probes to said power supplies via a switching matrix.
 - 14. A method according to claim 12, wherein each of said power supplies includes a feedback controller for adjusting a corresponding one of said plurality of first electrical signals based upon a corresponding one of said plurality of second electrical signals.
 - 15. A method according to claim 9, wherein said first electrical signal is provided via a forcing probe and a power supply in electrical communication with said forcing probe.
 - 16. A method according to claim 15, wherein said power supply includes a feedback controller for adjusting said first electrical signal based upon said second electrical signal.
- 1 17. A method according to claim 9, further comprising the step of providing a feedback signal in proportion to said second electrical signal for adjusting said first electrical signal.